

SIGC16T120CL

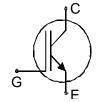
IGBT Chip in NPT-technology

FEATURES:

- 1200V NPT technology
- 180µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

This chip is used for:

chip only



Applications:

• drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code	
SIGC16T120CL	1200V	8A	4.04 x 4 mm ²	sawn on foil	Q67041-A4703-	
0.00.01.12002	1200 V	0/1	4.04 X 4 IIIIII	Sawii dii idii	A003	

MECHANICAL PARAMETER:

Raster size	4.04 x 4				
Area total / active	16.16 / 10.4				
Emitter pad size	1.88 x 2.18				
Gate pad size	0.71x1.08				
Thickness	180	μm			
Wafer size	150	mm			
Flat position	0	deg			
Max.possible chips per wafer	898 pcs				
Passivation frontside	Photoimide				
Emitter metalization	3200 nm Al Si 1%				
Collector metalization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500μm				
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				

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MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T _j =25 °C	V _{CE}	1200	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	24	Α
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_{j} =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
Tarameter		Conditions	min.	typ.	max.	0
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0 V , I_{C} =500 μ A	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =8A	1.8	2.2	2.6	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	I_C =350 μ A , V_{GE} = V_{CE}	4.5	5.5	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			1.1	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			120	nA

DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
raiailletei	Symbol	Conditions	min.	typ.	max.	Oille
Input capacitance	Ciss	V _{CE} =25V,	-	556	-	pF
Output capacitance	Coss	$V_{GE}=0V$,	-	-	-	
Reverse transfer capacitance	Crss	f=1MHz	-	38	-	

SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

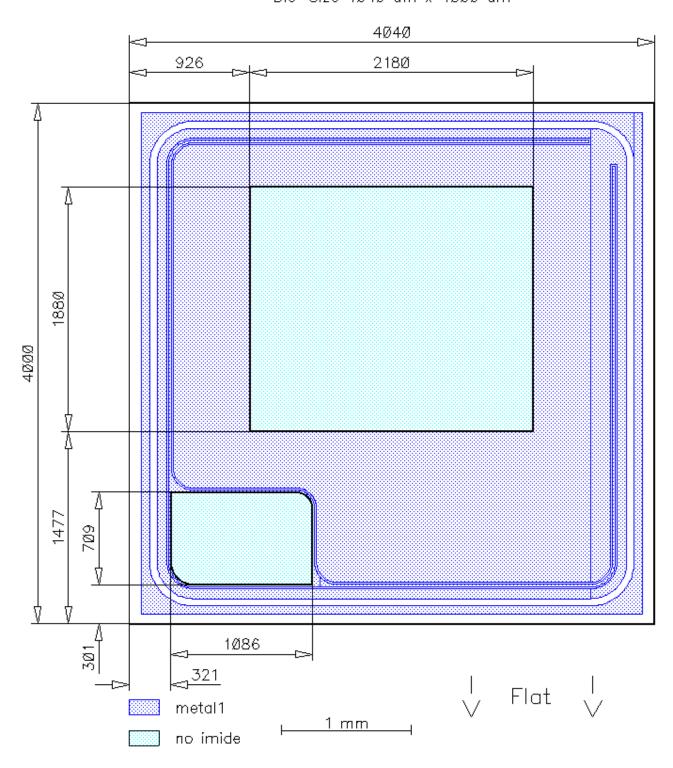
Parameter	Symbol	Conditions 1)	Value			Unit
- arameter	Cymbol	Conditions	min.	typ.	max.	
Turn-on delay time	$t_{d(on)}$	T _j =125°C	-	45	-	ns
Rise time	t_{r}	V _{CC} =600V, I _C =10A	-	40	-	
Turn-off delay time	$t_{d(off)}$	$V_{\rm GE}$ =±15V, $R_{\rm G}$ =82 Ω	-	285	-	
Fall time	t_{f}	/\G-0232	-	60	-	

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:

Die-Size 4040 um x 4000 um





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FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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